ISC Audits & Reviews SC Summary (May 20th, 2025)

Doc.	Title	Vote
7139-LI1;	Changes to E40 and E40.1 as shown ;	Passed
7140-LI1;	Changes to E94 and E94.1 as shown ;	Passed
7166;	Revision to SEMI PV79-0818, Test Method for Exposure Durability of Photovoltaic (PV) Cells to Acetic Acid Vapor;	Passed
7249;	Revision to SEMI PV81-0318, Guide for Specifying Low Pressure Horizontal Diffusion Furnace;	Passed
7294;	Reapproval of SEMI D65-0719, Test Method for Measurement for the Color Breakup of Field Sequential Color Display;	Passed
7295;	Reapproval of SEMI D68-0719, Test Method for Optical Properties of Electronic Paper Displays;	Passed
7313;	Reapproval of SEMI PV90-0319, Guide for Material Requirements of Internal Feeders Used in Mono-crystal Silicon Growers;	Passed
7316;	Revision to SEMI E90-1224 – Specification for Substrate Tracking and SEMI E90.1-1224- Specification for SECS-II Protocol Substrate Tracking	Passed
7318;	New Standard: Test Method for Net Carrier Density And Resistivity Of Silicon Epitaxial Layer By Capacitance-Voltage Measurements With An Evaporated Metal Schottky Diode;	Passed
7330-LI1;	Delete International SEMATECH Documents from Other Documents Section.;	Passed
R7130C;	Ratification Ballot, New Standard: Test Method Using Adhesive Replacement Substrates to Assess Particulate Surface Contamination of Critical Chamber Components;	Passed
R7240B;	Ratification Ballot, Revision to SEMI E157-0324, Specification for Module Process Tracking, with title change to: Specification for Module and Substrate Process Tracking;	Passed

For more information, please contact the SEMI Standards Engineer/Coordinator.
(http://www.semi.org/standards/contacts) nearest you.

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May 20th, 2025